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United States Patent [19]

Wakabayashi

[11] **Patent Number: Des. 411,809**

[45] **Date of Patent: ** Jul. 6, 1999**

[54] **SURVEYING APPARATUS/INSTRUMENTS**

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[**] Term: **14 Years**

[21] Appl. No.: **29/095,079**

[22] Filed: **Oct. 15, 1998**

[30] **Foreign Application Priority Data**

May 18, 1998 [JP] Japan 10-13676

[51] **LOC (6) Cl.** **10-04**
[52] **U.S. Cl.** **D10/66**
[58] **Field of Search** D10/66; 33/290–299; 356/138–155

[56] **References Cited**

U.S. PATENT DOCUMENTS

D. 375,464 11/1996 Hoshino D10/66
D. 389,418 1/1998 Takayama et al. D10/66

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[57] **CLAIM**

The ornamental design for surveying apparatus/instruments, as shown and described.

DESCRIPTION

FIG. **1** is a front view of the new surveying apparatus/instruments design;

FIG. **2** is a left-sided view thereof;

FIG. **3** is a top view thereof;

FIG. **4** is a right-sided view thereof;

FIG. **5** is a rear view thereof; and,

FIG. **6** is a bottom view thereof.

1 Claim, 2 Drawing Sheets

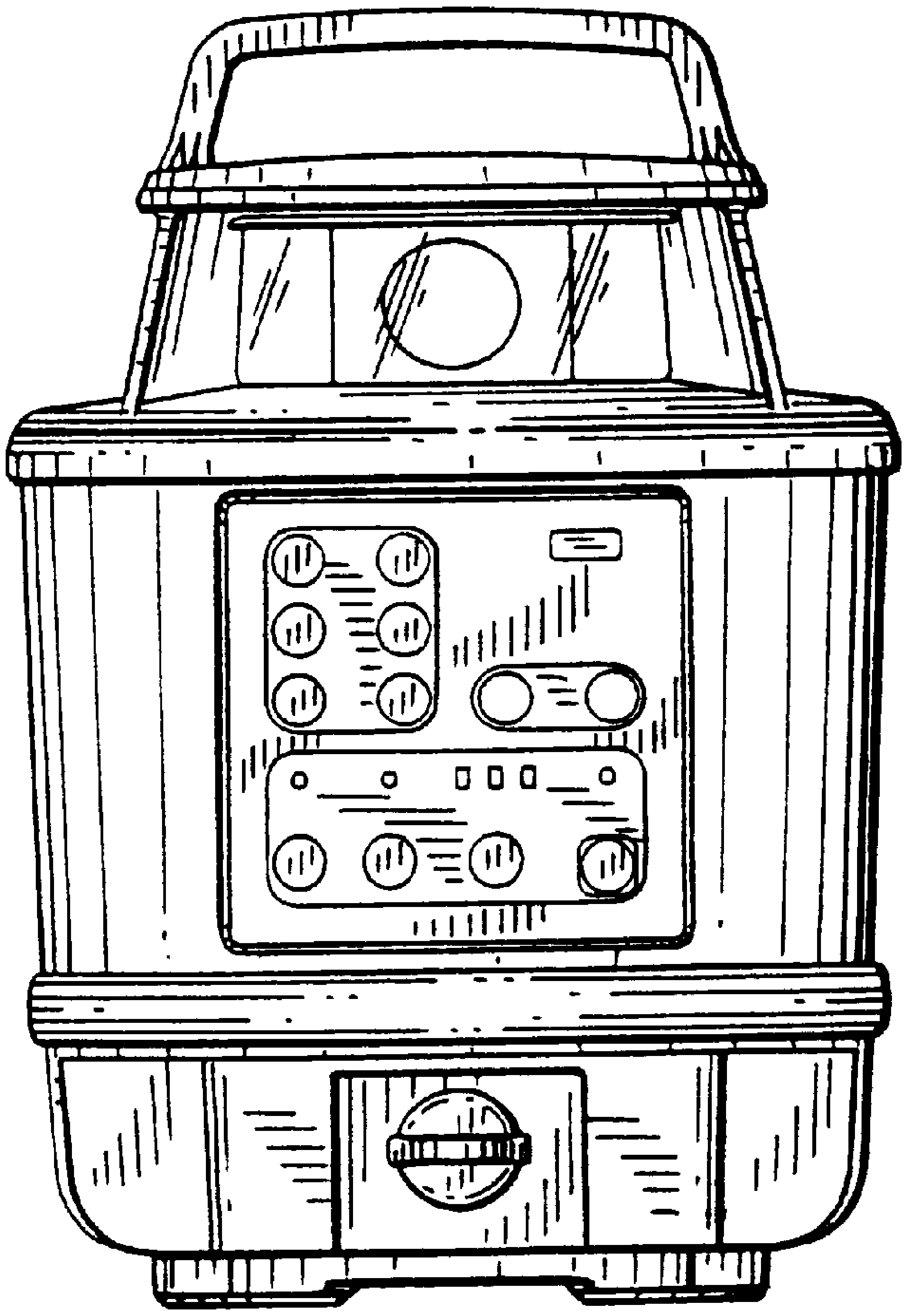
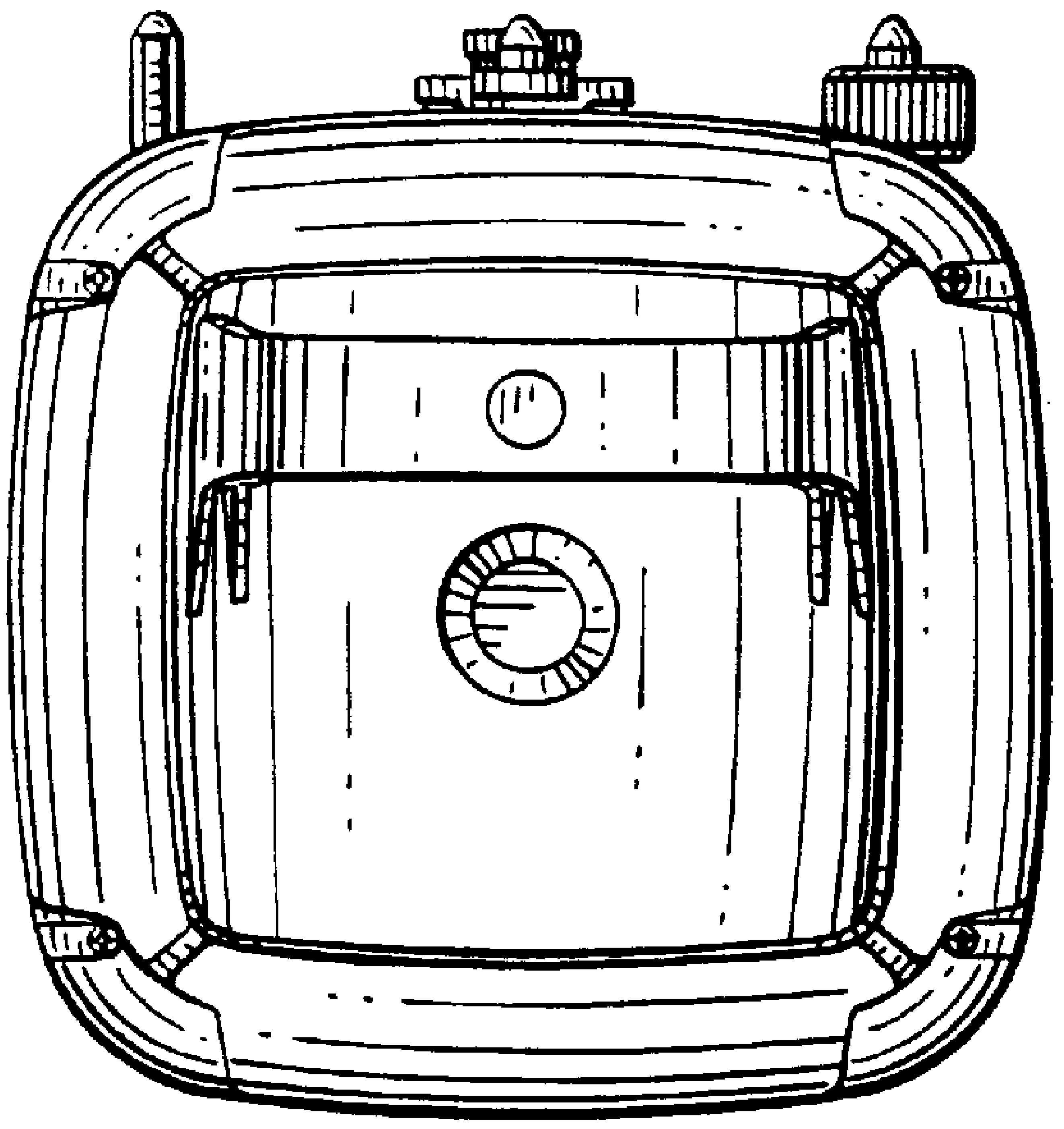


FIG.3



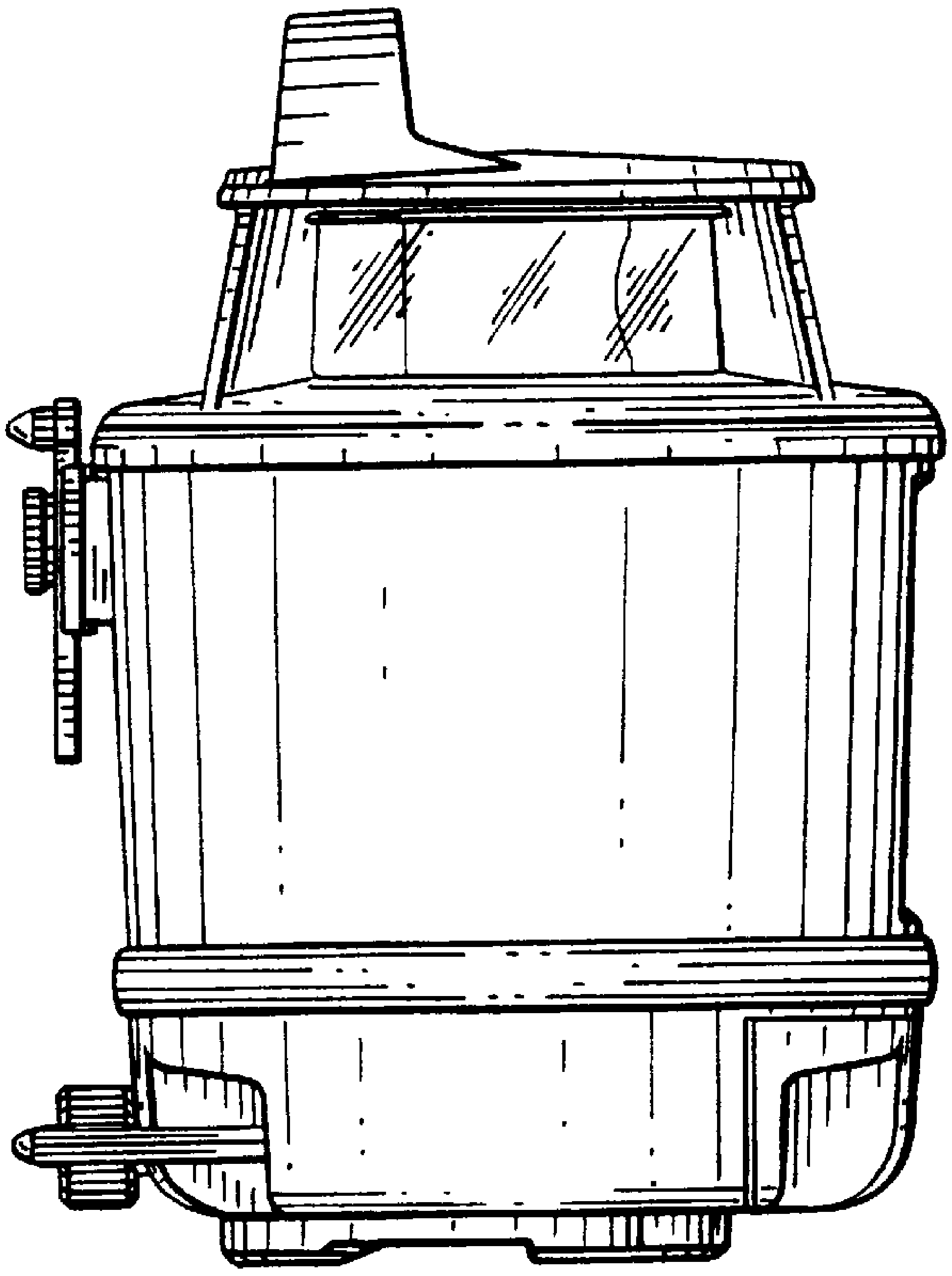
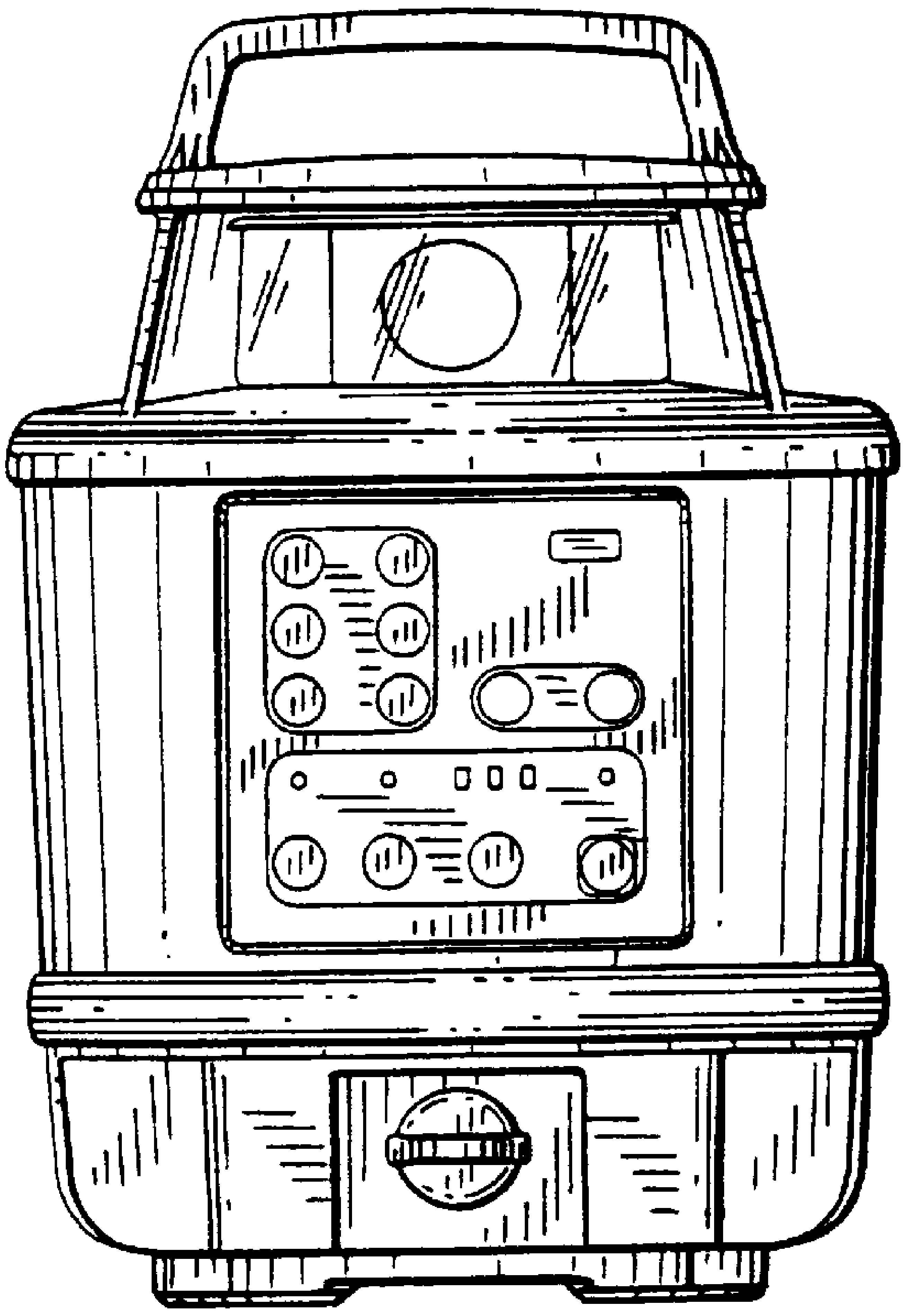


FIG.2

FIG.1



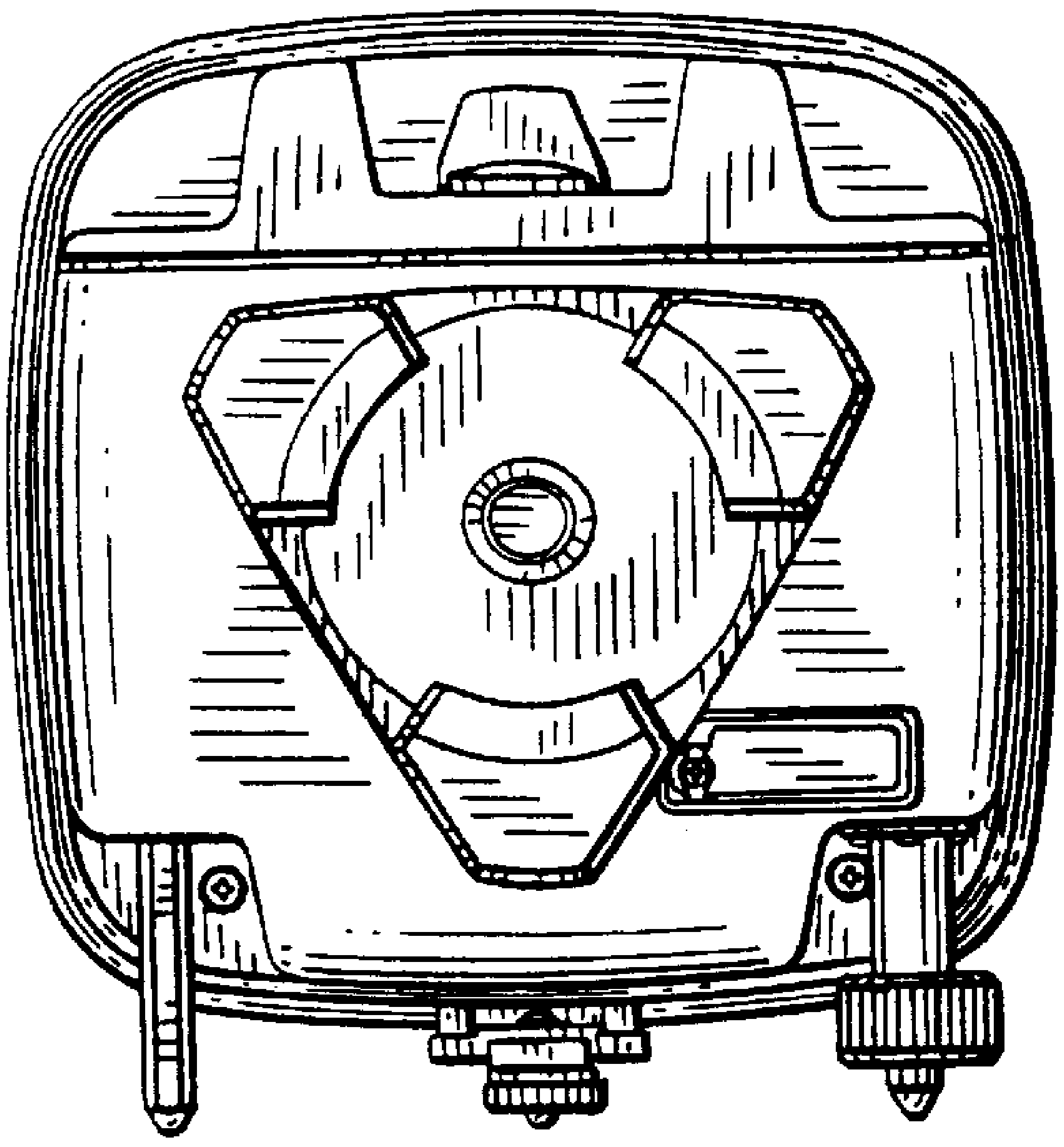
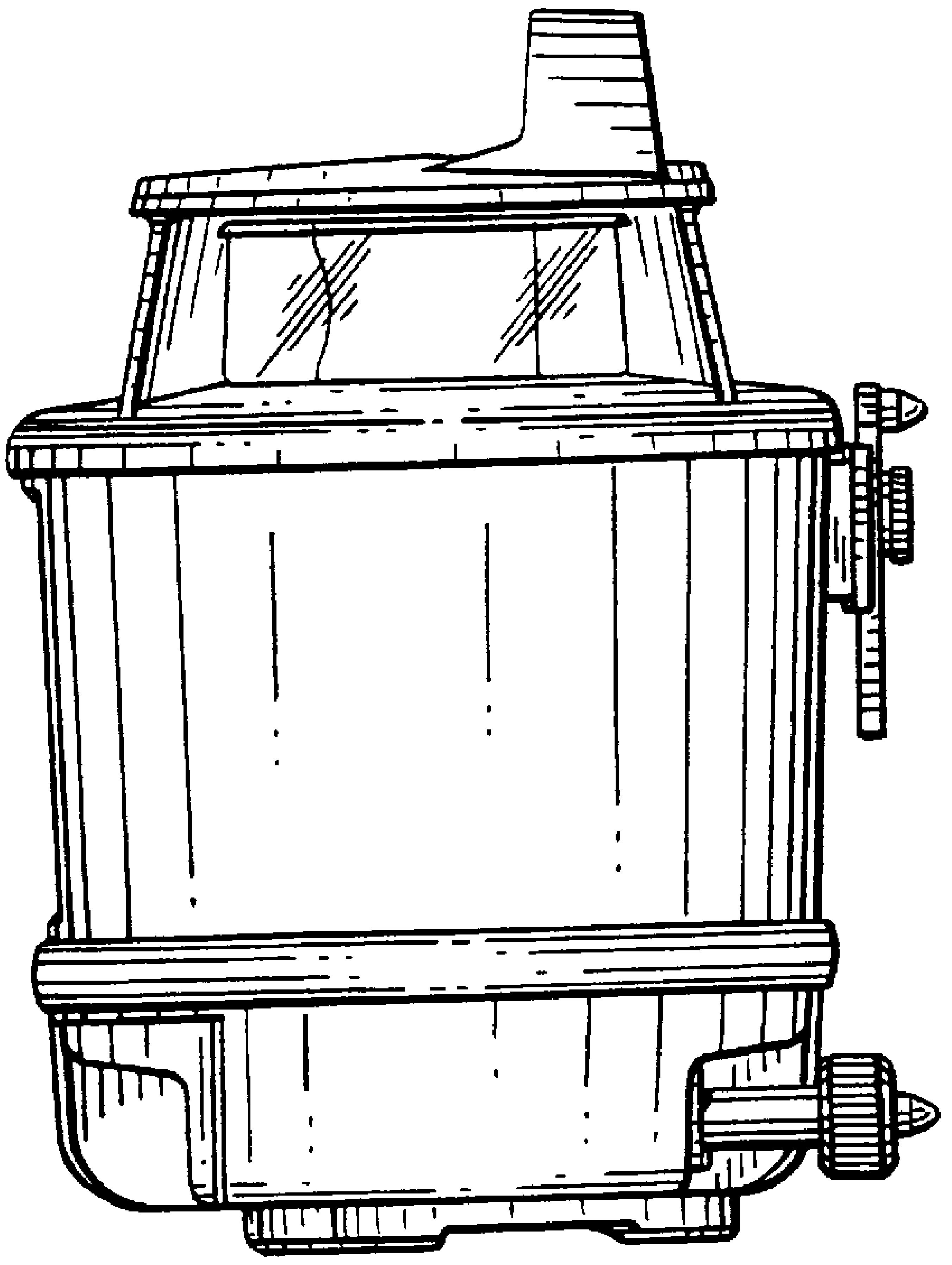


FIG.6

FIG.4



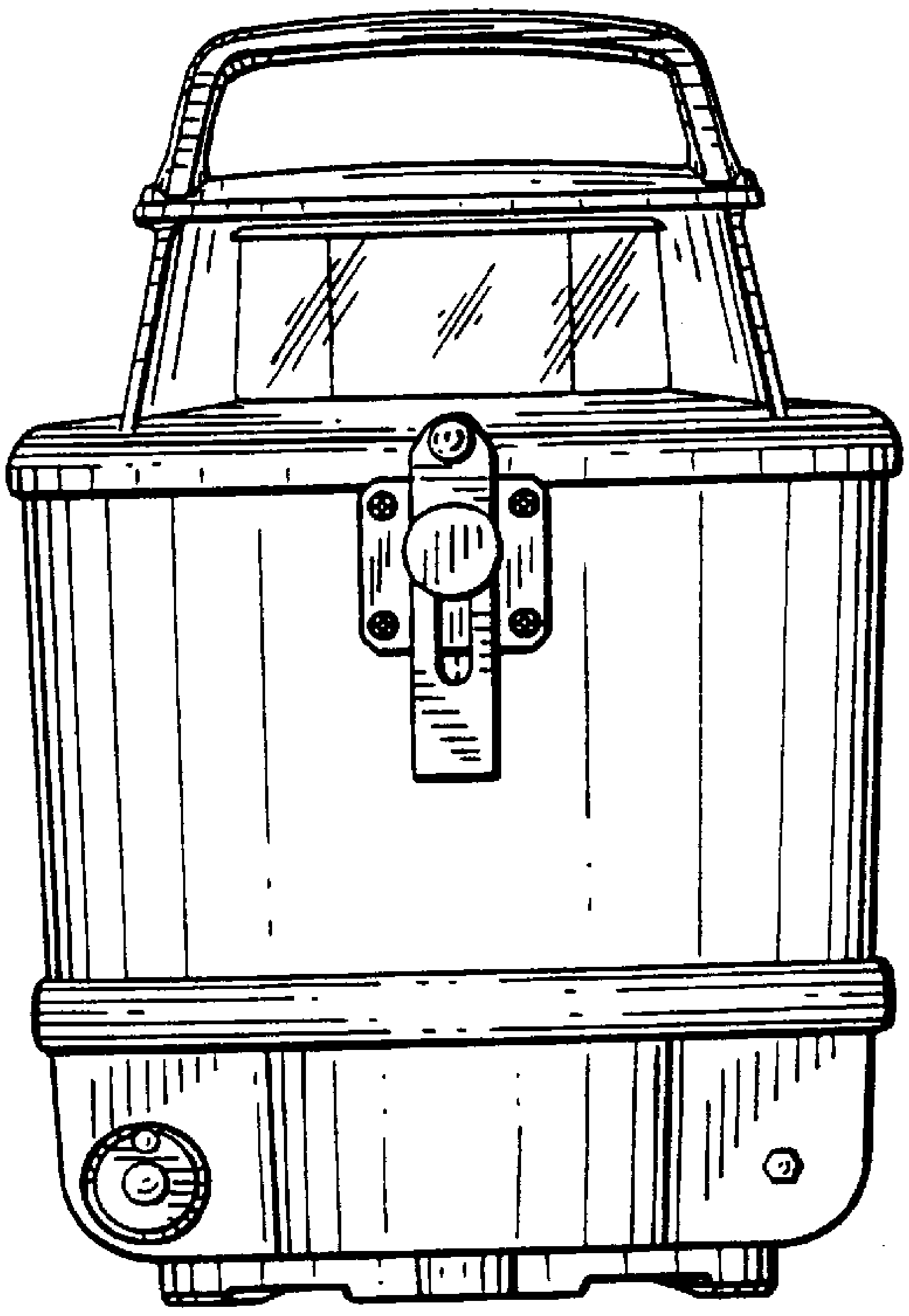


FIG.5